ESREF 2018 Conference

Provisional Programme Ver.09: 21-08-2018

	Monday, October 1 Tuesday, October 2										Wednesday, October 3					Thursday, October 4					Friday, October 5				
	om A	Room B	Room C	Room D	Exhibition area		Room A	Room B	Room C	Room D	Exhibition area		Room A	Room B	Room C	Room D	Exhibition area	Room A	Room B	Room C	Room D	Exhibition area			
	R	TUTORIAL teliability issues in power SiC and GaN				08.60 08.00 08.00 08.00 08.00 08.00 08.00 08.00 08.00				Industrial session	Exhibition	1 08.60 08.00 08.00 08.10 08.30 08.40 08.60 10.00	E2-3 (4)	L-1 (4)	SS1-1 (4)	Industrial session	Exhibition (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33) (0.33)	C-2 (5)			ECPE Workshop: Frontiers in reliability engineering: railway traction, renewables, industry	Exhibition	1 0840 6850 6850 6850 6850 6850 6830 6850 6850		
		TUTORIAL Reliability of	TUTORIAL Dielectric		Exhibition set up	10.10 10.20 10.30 10.40 10.60 11.00	Invited B. Linder				Coffee break	10.60 10.60 11.00	Invited F. Altmann	Invited M.B. Tahoori		Workhop:	10.20 10.30 10.40 10.60					Coffee break	1010 1020 1030 1040 1080 1160		
		packages for	relability in microelectronics			11.50 11.30 11.30 11.40 11.50 12.00	E1-3 (3)	A-2 (3)	Best Paper IPFA B1-1 (3)	Industrial session	Exhibition	11:10 11:30 11:30 11:40 11:40 12:00 12:10	F-2 (4)			Reliability in innovative Automotive ICs	Exhibition 10.10 1	0-5 (5)			Workshop: Condition and health monitoring	Exhibition	11.00 11.20 11.30 11.60 11.60 12.00		
					Lunch	12:50 12:30 12:30 12:40 12:60 13:00					Lunch	12:30 12:30 12:30 12:40 12:40 13:00 13:10					Lunch 15 15 15 15 15 15 15 15 15 15 15 15 15	Closing Session					1230 1230 1240 1240 1300		
		TUTORIAL Moisture Modeling in Complex	TUTORIAL Introduction to the modern reliability			13:30 13:30 13:40 13:50 14:00 14:10	Invited J. Lutz	Invited N. Stojadinovic				19:30 19:30 19:40 19:60 16:00 16:10	Invited R. Ambat	Invited P. Plăffii			13.30 13.30 13.43 13.60 14.00					Lunch	13.10 13.20 13.30 13.60 13.60 14.00		
	g session	Systems			Exhibition set up	16:30 16:30 16:40 16:80 16:00 16:10 16:20			B1-2 (3)	Industrial session	Exhibition	16:30 16:30 16:40 16:50 16:00 16:10 16:30 16:30 16:40 16:50	F-3 (5)			Workshop: Applied robustness	Exhibition (520 1520 1520 1520 1520 1520 1520 1520 1	Symposium				Exhibition dismantling	1420 1430 1440 1450 1550 1510 1520		chnical Tec isit 1 vi
P. G	/note largini /note Kjaer					16.40 16.60 16.00 16.10			Best Paper IRPS		Coffee break			Best paper ISTFA		validation	16.20 16.40 16.40 16.00 16.00					Coffee break	16.00 16.60 16.60 16.00 16.10		
		F-1 (3)	C-1 (3)	K-1 (2)	Coffee break Exhibition	16:30 16:40 16:50 17:00 17:10			B3 (3)	Industrial session		16:30 16:40 16:50 17:00 17:10 17:30					98.30 98.40 98.60 97.00 97.00	Symposium				Exhibition dismantling	16:30 16:60 16:60 17:00 17:10 17:20		
	1 (3)	F-1 (3)	C-1 (3)		set up	17:30 17:40 17:50 18:00 18:10					Exhibition	17:40 17:60 16:00					17:30 17:40 17:40 16:00 16:00 16:20						1730 1740 1750 1800 1810 1820		
					Aalborg City buffet	18.30 18.40 18.60 19.00 19.10 19.30 19.30 19.60		Poster s	ession			18:30 18:30 18:40 18:80 19:00 19:10		Tou	ır & Social d	inner	18.30 18.60 18.00 18.00 18.00						18.00 18.00 18.00 19.00 19.10		
					z.i, June	20.00 20.10 20.20		Vouna Pr	ofaccional Pa	cention		19:30 19:30 19:40 19:50 20:10 20:10 20:20 20:30 20:40					19.30 19.40 19.50 20.00 20.00 20.00						19:30 19:40 19:50 20:30 20:10 20:20		
						20:30 20:40 20:50		Young Professional Reception				20:30 20:40 20:50	530 East 90.90				20 30 20 40 20 50	20.33 20.40 20.91 127.00				2030 2040 2050			

- Tracks
 A Quality and Reliability Assessment Techniques and Methods for Devices and Systems B1 Si-Technologies & Nanoelectronics: Hot Carriers, High-K, Cate Materials B2 Si Technologies & Nanoelectronics: ELOW-K, Cu Interconnects B3 Si-Technologies & Nanoelectronics: ESD BMI and Latch-up C Progress in Failure Analysis: Defect Detection and Analysis
 D Reliability of Microwave and Compound Samiconductors Devices
 E1 Power Devices Reliability Silicon and Passive
 E2 Power Devices Reliability Wide Bandgap Devices
 F Packaging and Assembly Reliability
 G MEMS, Sensors and Orancia Electronics Reliability
 H Photonics Reliability
 I Extreme Environments and Radiation
 K Renewable Energies Reliability
 L Modeling for Reliability
 S31 Reliability in Traction Applications